

FORM PTO-1449 SAMUELS, GAUTHIER & STEVENS LLP
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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

ATTORNEY DOCKET NO. MIT9888
Pitera et al.
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SERIAL NO. Unknown
GROUP: Unknown
EXAMINER: Unknown

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BK	AA	5,882,987	3/16/99	Srikrishnan	—	—	8/26/97
BK	AB	5,374,564	12/20/94	Bruel	—	—	9/15/92
BK	AC	6,573,126	6/3/03	Cheng et al.	—	—	8/10/01
BK	AD	6,475,072	11/5/02	Camafero et al.	—	—	9/29/00
BK	AE	6,107,653	8/22/00	Fitzgerald	—	—	9/29/00
BK	AF	6,150,239	11/21/00	Goesele et al.	—	—	9/30/98
BK	AG	5,877,070	3/2/99	Goesele et al.	—	—	3/31/97

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
—	AH	—	—	—	—	—	—

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
BK	AI	"Silicon on Insulator Material Technology"; M. Bruel; Electronics Letters; July 6, 1995; Vol. 31, No. 14; pgs: 12011202
BK	AJ	"Ge layer transfer to Si for photovoltaic applications"; Zahler et al., Thomas J. Watson Laboratory of Applied Physics, California Institute of Technology; pgs.: 558-562
BK	AK	"Transfer of 3 in GaAs film on silicon substrate by proton implantation process"; Jalaguier et al., Electronics Letters; February 19, 1998; Vol. 34, No. 4; pgs.: 408-409
BK	AL	"Electron Mobility Enhancement in Strained-Si n-MOSFETs Fabricated on SiGe-on Insulator (SGOI) Substrates"; Cheng et al., IEEE Electron Device Letters; Vol. 22, No. 7, July 2001; pgs.: 321-323
BK	AM	"Preparation of Novel SiGe-Free Strained Si on Insulator Substrates"; Langdo et al., IEEE International SOI Conference; 2002; pgs.: 211-212
BK	AN	"Cleaning and Polishing As Key Steps For Smart-Cut SOI Process"; Moriceau et al., IEEE International SOI Conference, October 1996; pgs: 152-153
BK	AO	"Relaxed Silicon-Germanium on Insulator Substrate By Layer Transfer"; Cheng et al., Journal of Electronic Materials; Vol. 30, No. 12; 2001; pgs.: L37-L39

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Bruel

DATE CONSIDERED

09/13/04

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Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BK	AA	5,462,883	10/31/1995	Dennard et al.	—	—	04/11/1994
BK	AB	6,059,895	05/09/2000	Chu et al.	—	—	05/13/1999
	AC						
	AD						
	AE						
	AF						
	AG						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
BK	AH	WO 02/15244	02/21/2002	PCT	—	—	YES
BK	AI	WO 02/33746	04/25/2002	PCT	—	—	YES
BK	AJ	WO 02/13342	02/14/2002	PCT	—	—	YES
BK	AK	101 00 194 A1	07/19/2001	DE	—	—	NO
BK	AL	2 777 116	10/08/1999	FR	—	—	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
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